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## Semiconductor devices – Discrete devices –

### Part 7-5: Bipolar transistors for power switching applications

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## SEMICONDUCTOR DEVICES – DISCRETE DEVICES –

## Part 7-5: Bipolar transistors for power switching applications

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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## SEMICONDUCTOR DEVICES – DISCRETE DEVICES –

### Part 7-5: Bipolar transistors for power switching applications

#### 1 Scope

This part of IEC 60747 gives requirements for bipolar switching transistors used for power switching application above 1 A.

NOTE Requirements concerning bipolar transistors in general can be found in IEC 60747-7.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-7, *Semiconductor devices – Part 7: Bipolar transistors*

IEC 60747-1:1983, *Semiconductor devices – Discrete devices and integrated circuits – Part 1: General*